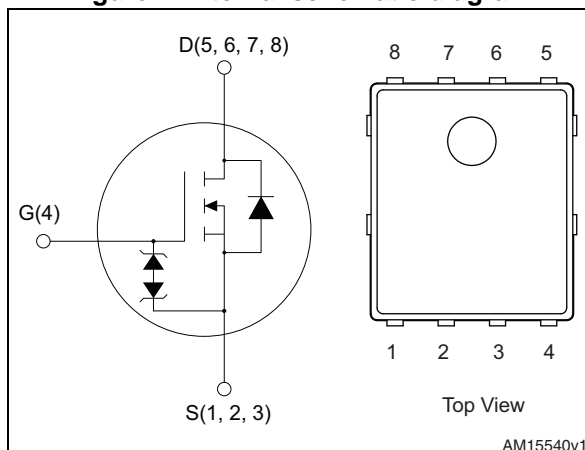


## N-channel 800 V, 2.1 $\Omega$ typ., 2.5 A Zener-protected SuperMESH™ 5 Power MOSFET in a PowerFLAT™ 5x6 VHV package

Datasheet – production data



**Figure 1. Internal schematic diagram**



### Features

Order code	$V_{DS}$	$R_{DS(on)max.}$	$I_D$
STL4N80K5	800 V	2.5 $\Omega$	2.5 A

- Outstanding  $R_{DS(on)}$ \* area
- Worldwide best FOM (figure of merit)
- Ultra low gate charge
- 100% avalanche tested
- Zener protected

### Applications

- Switching applications

### Description

This N-channel Zener-protected Power MOSFET is designed using ST's revolutionary avalanche-rugged very high voltage SuperMESH™ 5 technology, based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance, and ultra-low gate charge for applications which require superior power density and high efficiency.

**Table 1. Device summary**

Order code	Marking	Package	Packaging
STL4N80K5	4N80K5	PowerFLAT™ 5x6 VHV	Tape and reel

# Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$	2.5	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	1.55	A
$I_{DM}^{(1),(2)}$	Drain current (pulsed)	10	A
$P_{TOT}^{(1)}$	Total dissipation at $T_C = 25\text{ }^\circ\text{C}$	38	W
$I_{AR}^{(3)}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)	1	A
$E_{AS}^{(4)}$	Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	74.5	mJ
$dv/dt^{(5)}$	Peak diode recovery voltage slope	4.5	V/ns
$dv/dt^{(6)}$	MOSFET $dv/dt$ ruggedness	50	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature		$^\circ\text{C}$

1. The value is rated according to  $R_{thj-case}$  and limited by package.
2. Pulse width limited by safe operating area.
3. Pulse width limited by  $T_{jmax}$
4. Starting  $T_j=25\text{ }^\circ\text{C}$ ,  $I_D=I_{AR}$ ,  $V_{DD}=50\text{ V}$
5.  $I_{SD} \leq 2.5\text{ A}$ ,  $di/dt \leq 100\text{ A}/\mu\text{s}$ ,  $V_{DS(peak)} \leq V_{(BR)DSS}$
6.  $V_{DS} \leq 640\text{ V}$

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	3.3	$^\circ\text{C}/\text{W}$
$R_{thj-amb}^{(1)}$	Thermal resistance junction-amb max	59	$^\circ\text{C}/\text{W}$

1. When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu.

## 2 Electrical characteristics

( $T_C = 25\text{ °C}$  unless otherwise specified)

**Table 4. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage ( $V_{GS} = 0$ )	$I_D = 1\text{ mA}$	800			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 800\text{ V}$ $V_{DS} = 800\text{ V}, T_C = 125\text{ °C}$			1 50	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20\text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 100\text{ }\mu\text{A}$	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}, I_D = 1.5\text{ A}$		2.1	2.5	$\Omega$

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100\text{ V}, f = 1\text{ MHz},$ $V_{GS} = 0$	-	175	-	pF
$C_{oss}$	Output capacitance		-	20	-	pF
$C_{riss}$	Reverse transfer capacitance		-	1	-	pF
$C_{o(tr)}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0\text{ to }640\text{ V}, V_{GS} = 0$	-	26	-	pF
$C_{o(er)}^{(2)}$	Equivalent capacitance energy related		-	11	-	pF
$R_G$	Intrinsic gate resistance	$f = 1\text{ MHz}, I_D = 0$	-	15	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 640\text{ V}, I_D = 3\text{ A},$ $V_{GS} = 10\text{ V}$ (see <a href="#">Figure 16</a> )	-	10.5	-	nC
$Q_{gs}$	Gate-source charge		-	2	-	nC
$Q_{gd}$	Gate-drain charge		-	7.5	-	nC

1.  $C_{oss\text{ eq.}}$  time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$
2.  $C_{oss\text{ eq.}}$  energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 400\text{ V}$ , $I_D = 1.5\text{ A}$ , $R_G = 4.7\text{ }\Omega$ , $V_{GS} = 10\text{ V}$ (see <a href="#">Figure 15</a> ), (see <a href="#">Figure 20</a> )	-	16.5	-	ns
$t_r$	Rise time		-	15	-	ns
$t_{d(off)}$	Turn-off delay time		-	36	-	ns
$t_f$	Fall time		-	21	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		2.5	A
$I_{SDM}$	Source-drain current (pulsed)		-		10	A
$V_{SD}^{(1)}$	Forward on voltage	$I_{SD} = 3\text{ A}$ , $V_{GS} = 0$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 3\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$ (see <a href="#">Figure 17</a> )	-	242		ns
$Q_{rr}$	Reverse recovery charge		-	1.42		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	12		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 3\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$ , $T_j = 150\text{ }^\circ\text{C}$ (see <a href="#">Figure 17</a> )	-	373		ns
$Q_{rr}$	Reverse recovery charge		-	1.98		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	10.5		A

1. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1\text{ mA}$ , $I_D = 0$	30	-	-	V

The built-in back-to-back Zener diodes have been specifically designed to enhance not only the device's ESD capability, but also to make them capable of safely absorbing any voltage transients that may occasionally be applied from gate to source. In this respect, the Zener voltage is appropriate to achieve efficient and cost-effective protection of device integrity. The integrated Zener diodes thus eliminate the need for external components.

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

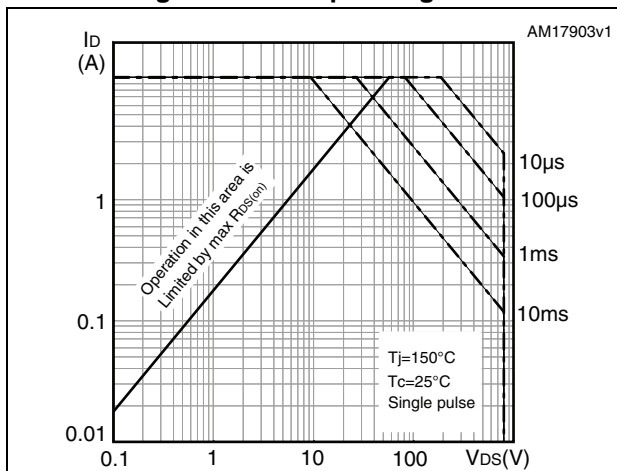


Figure 3. Thermal impedance

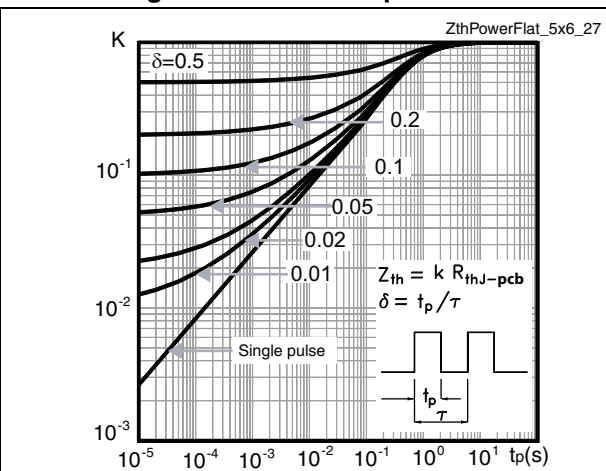


Figure 4. Output characteristics

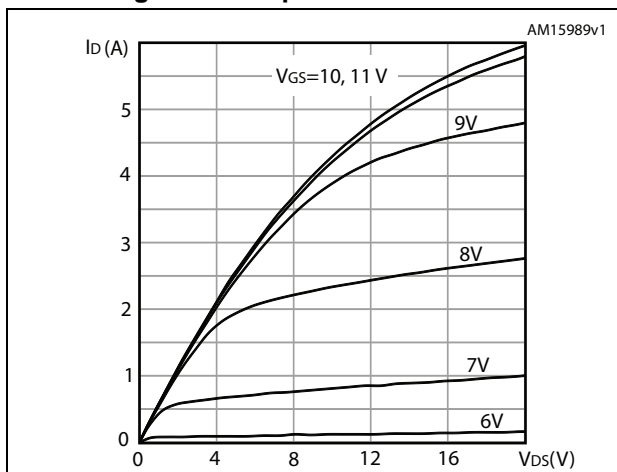


Figure 5. Transfer characteristics

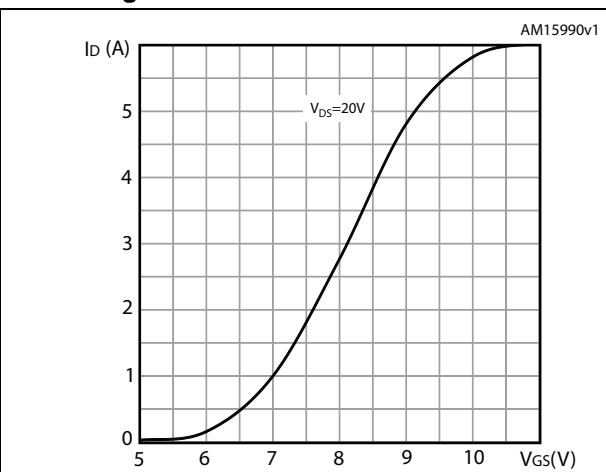


Figure 6. Gate charge vs gate-source voltage

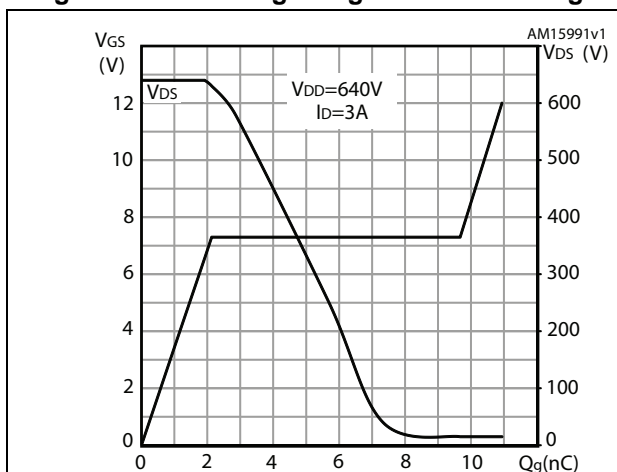


Figure 7. Static drain-source on-resistance

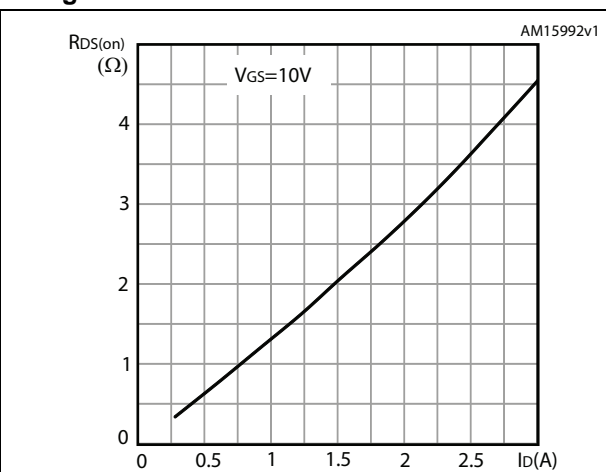


Figure 8. Capacitance variations

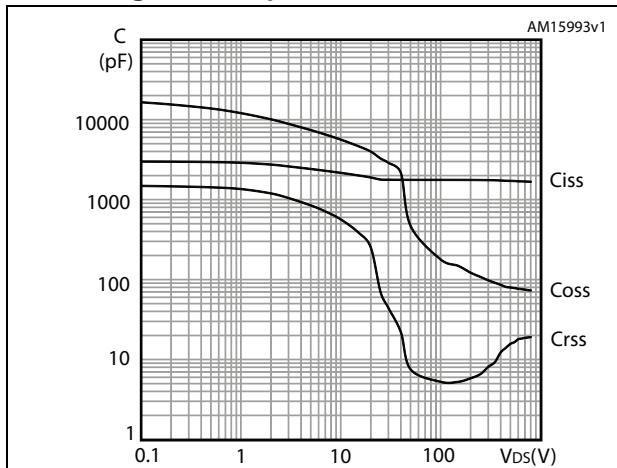


Figure 9. Output capacitance stored energy

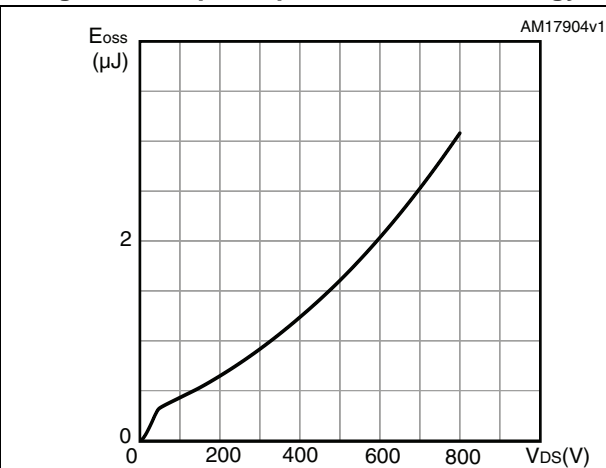


Figure 10. Normalized gate threshold voltage vs. temperature

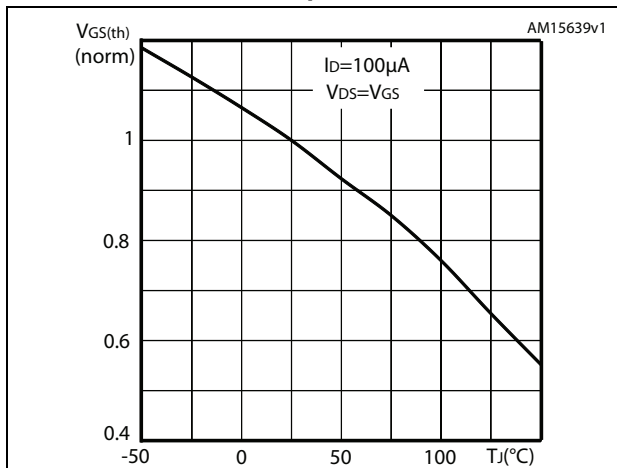


Figure 11. Normalized on-resistance vs. temperature

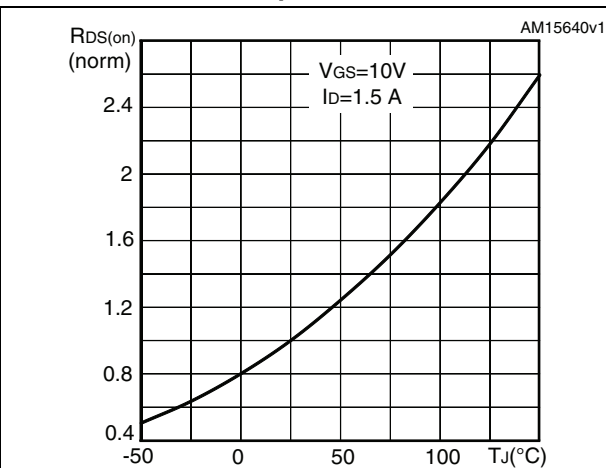


Figure 12. Drain-source diode forward characteristics

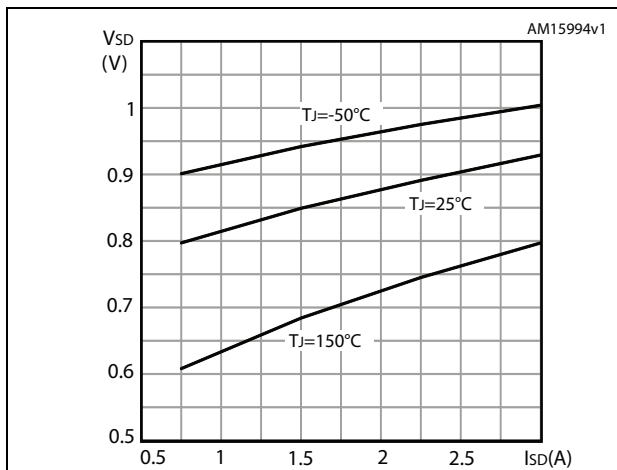


Figure 13. Normalized V<sub>DS</sub> vs. temperature

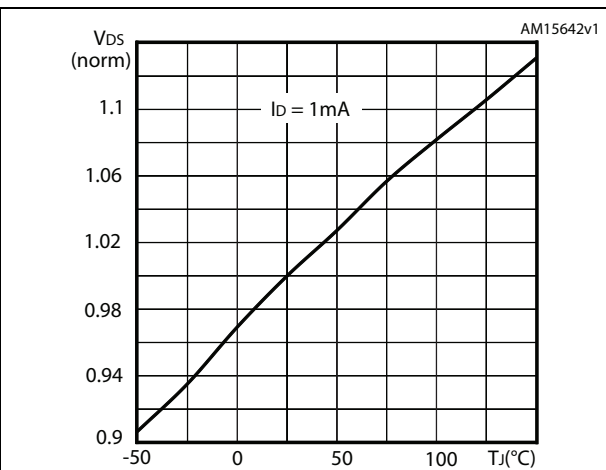
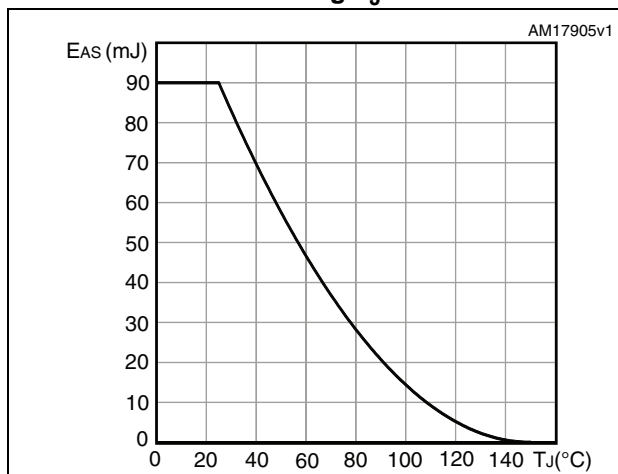


Figure 14. Maximum avalanche energy vs. starting  $T_J$





### 3 Test circuits

Figure 15. Switching times test circuit for resistive load

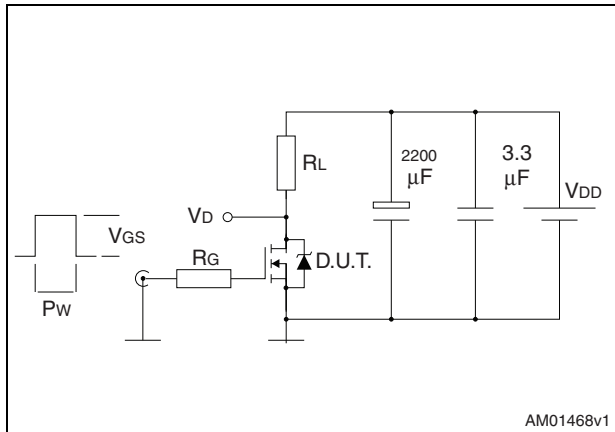


Figure 16. Gate charge test circuit

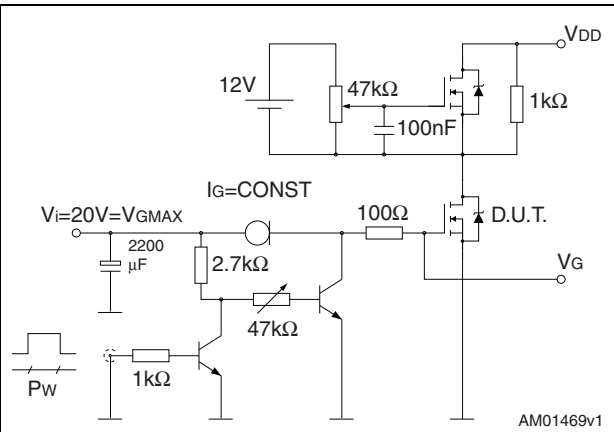


Figure 17. Test circuit for inductive load switching and diode recovery times

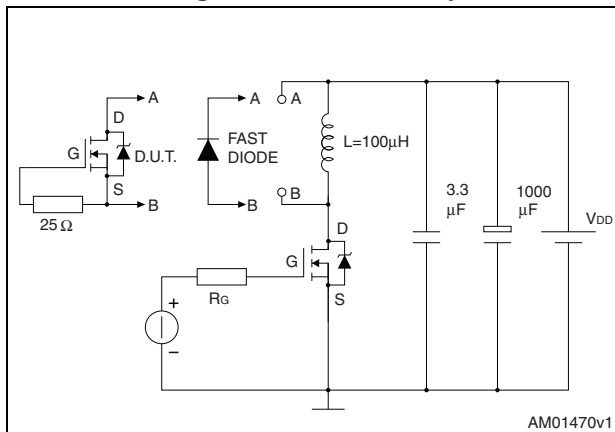


Figure 18. Unclamped inductive load test circuit

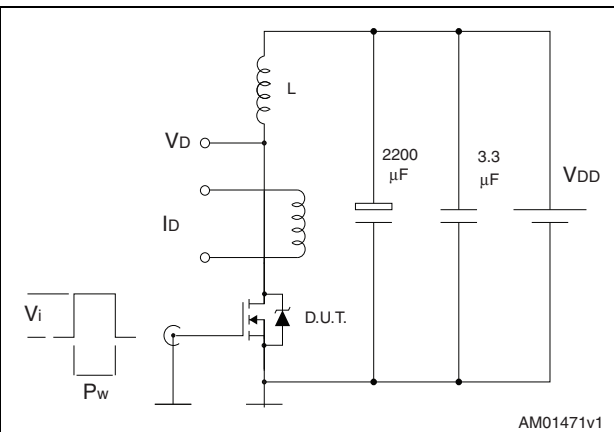


Figure 19. Unclamped inductive waveform

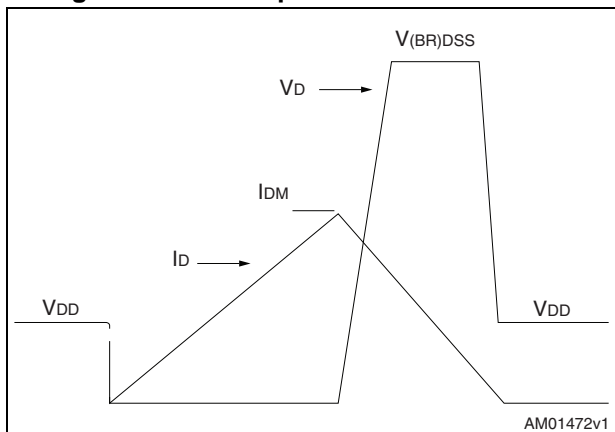
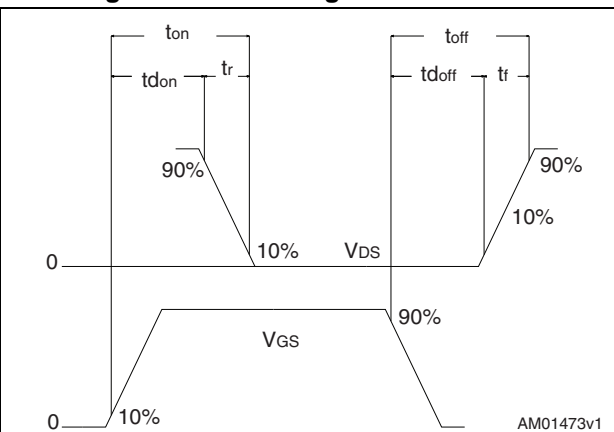


Figure 20. Switching time waveform



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK<sup>®</sup> is an ST trademark.

Table 9. PowerFLAT™ 5x6 VHV mechanical data

DIM	mm.		
	min.	typ.	max.
A	0.80		1.00
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
D	5.00	5.20	5.40
E	5.95	6.15	6.35
D2	4.30	4.40	4.50
E2	2.40	2.50	2.60
e		1.27	
L	0.50	0.55	0.60
K	2.60	2.70	2.80

Figure 21. PowerFLAT™ 5x6 VHV

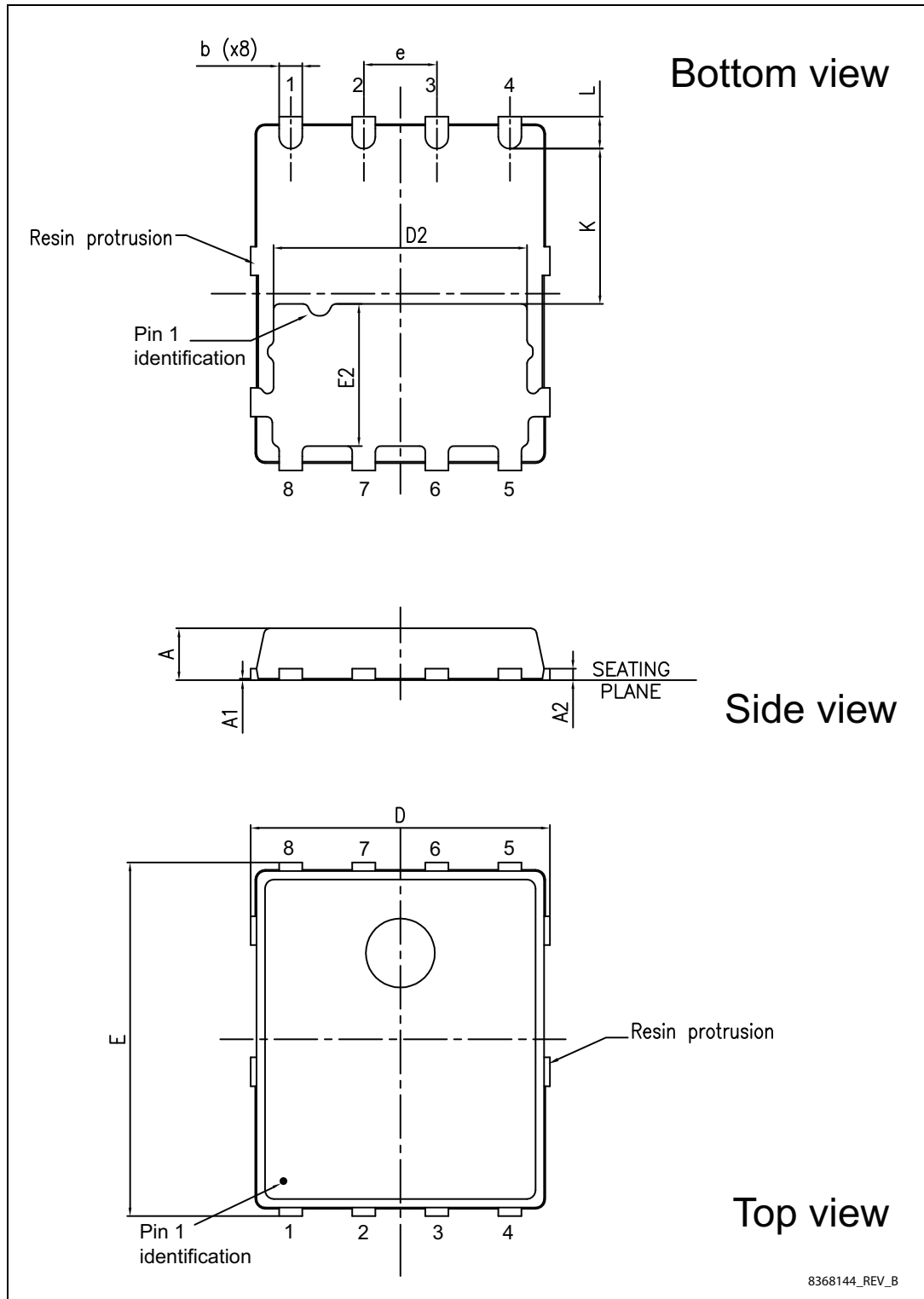
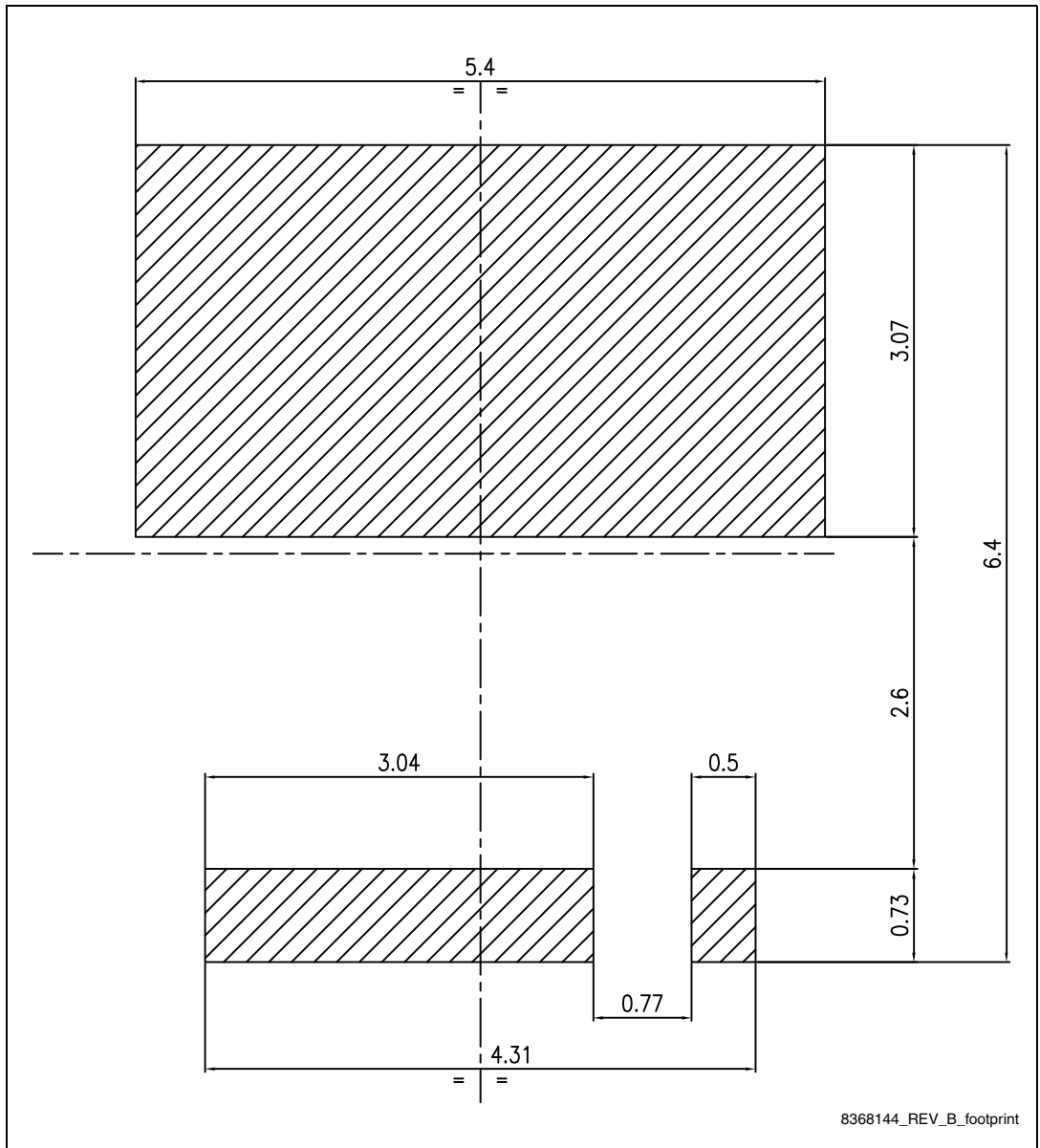


Figure 22. PowerFLAT™ 5x6 VHV (dimensions are in mm)



# 5 Packaging mechanical data

Figure 23. PowerFLAT™ 5x6 tape

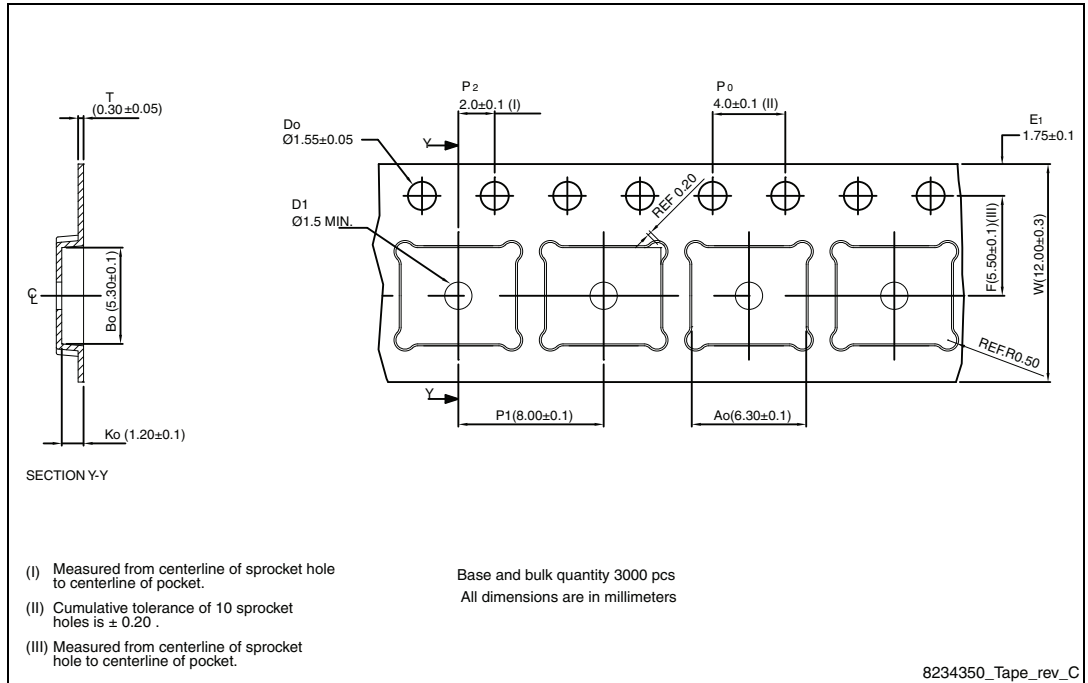


Figure 24. PowerFLAT™ 5x6 package orientation in carrier tape

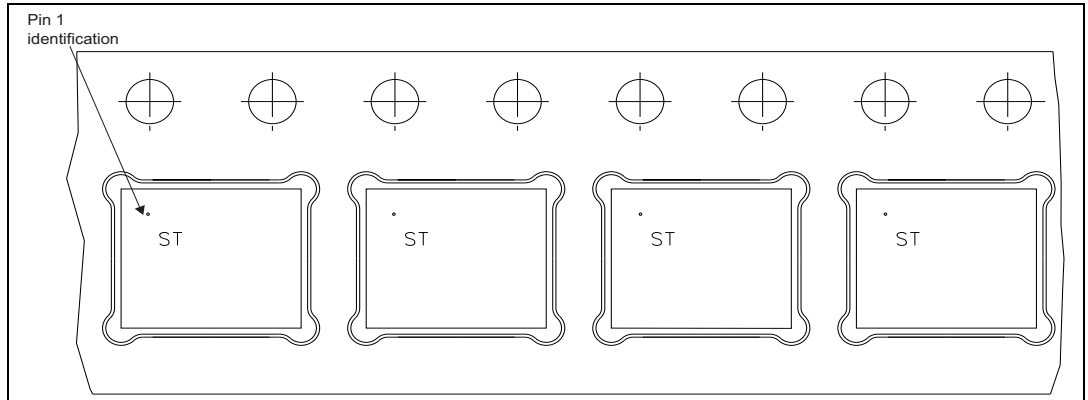
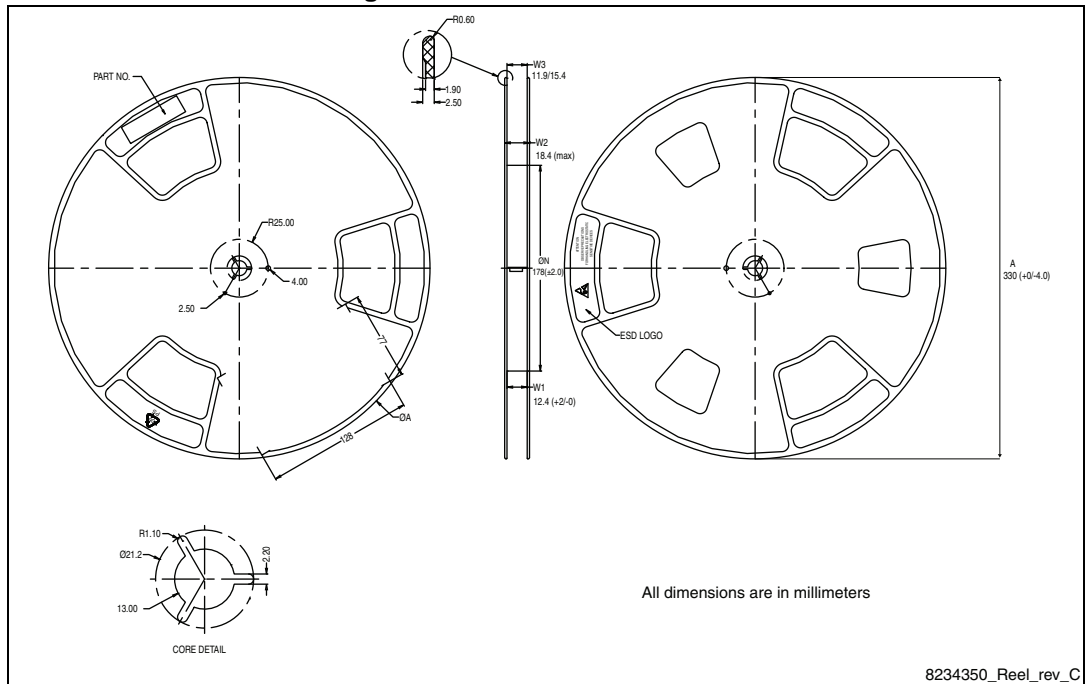


Figure 25. PowerFLAT™ 5x6 reel



## 6 Revision history

Table 10. Document revision history

Date	Revision	Changes
22-Nov-2013	1	First release.



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